Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/705,890	OESCH, YVES	
Examiner	Art Unit	
Duc M. Nguyen	2685	

SEARCHED					
Class	Subclass	Date	Examiner		
455	41.1 41.2 41.3				
	42->45				
	567				
	572				
	575.6				
	90.1-> ′				
	->90.3				
	59 106				
	347->349				
379	428.02				
	433.1				
	433.11				
	441 443				
	447	2/15/2006	DN		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
claim	search	6/15/06	100 N		
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(INCLUDIN	EARCH NOT	STRATEGY)
		DATE	EXMR
EAST		2/15/2006	DN
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